

# Abstracts

## The Application of "Thru-Short-Delay" to the Calibration of the Dual Six-Port

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*G.F. Engen and C.A. Hoer. "The Application of "Thru-Short-Delay" to the Calibration of the Dual Six-Port." 1978 MTT-S International Microwave Symposium Digest 78.1 (1978 [MWSYM]): 184-185.*

In a companion paper, in this digest, a scheme for reducing the (single) six-port calibration problem to that of an equivalent four-port reflectometer has been described. This now makes it possible to apply existing four-port calibration schemes. One such method is the "thru-short-delay" (TSD) procedure. This paper briefly outlines this calibration approach.

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